

Search Notes

Application/Control No.

09/544,523

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB) text search - see search history printout	7/11/2007	NT
348/333.01-333.12 (text search - see search history printout)	7/11/2007	NT